



Short Course Announcement Microwave Measurements for Digital Communication Systems



November 30 – Decemeber 1, 2004
Orlando, Florida

Do you need to commit this year's educational expenses soon? Are you an engineer, technician, or scientist concerned with accurate measurement of RF and microwave quantities? If so, it might be worth planning ahead. The Automatic Radio Frequency Techniques Group (ARFTG) in cooperation with the National Institute of Standards and Technology (NIST) will offer its 2004 Microwave Measurements Short Course in Orlando, Florida, on November 30 through noon, December 1. This course is held in conjunction with the 64th ARFTG Microwave Measurements Conference on December 2-3. The conference theme is, "Digital Communication System Metrics."

The 1 ½-day course covers microwave measurement fundamentals, including vector network analysis, scattering parameters, power, and thermal noise. Practical issues such as cables, fixtures, probes, and on-wafer measurements are covered. More advanced measurement topics are also covered including microwave measurements for optoelectronic applications, scattering-parameter uncertainty analysis, electromagnetic compatibility, and an overview of wireless test instrumentation and nonlinear measurements.

This course provides an excellent introduction for newcomers to the field or a good review for those familiar with RF and microwave measurements. The course registration fee is \$400 and includes lunch on both days. Lecture notes will be provided. Class size is limited. For more information on the conference and short course see www.arftg.org or contact

David K. Walker
NIST, M.S. 813.01
325 Broadway
Boulder, CO 80305
Phone: 303-497-5490 FAX: 303-497-3970
E-mail: dwalker@boulder.nist.gov